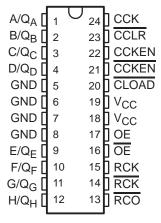
- Parallel 3-State I/O: Register Inputs/ Counter Outputs
- Counter Has Direct Overriding Load and Clear
- Flow-Through Architecture Optimizes
   PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

## DW OR NT PACKAGE (TOP VIEW)



### description

The 74AC11953 consists of a parallel input, an 8-bit storage register feeding an 8-bit counter, and a 3-state I/O which provides parallel count outputs. Both the register and the counter have individual positive-edge triggered clocks.

The function tables show the operation of the counter clock-enable (CCKEN, CCKEN) and output-enable (OE, OE) inputs. A register clock-enable (RCK) input is also provided.

The counter ( $\overline{RCO}$ ) input has direct load and clear functions. A low-going  $\overline{RCO}$  pulse will be obtained when the counter reaches the hex word FF. Expansion is easily accomplished for two stages by connecting  $\overline{RCO}$  of the first stage to  $\overline{CCKEN}$  of the second stage. Cascading for larger count chains can be accomplished by connecting  $\overline{RCO}$  of each stage to  $\overline{CCK}$  of the following stage.

The 74AC11593 is characterized for operation from  $-40^{\circ}$ C to 85°C.

### **Function Tables**

#### **COUNTER CLOCK ENABLE**

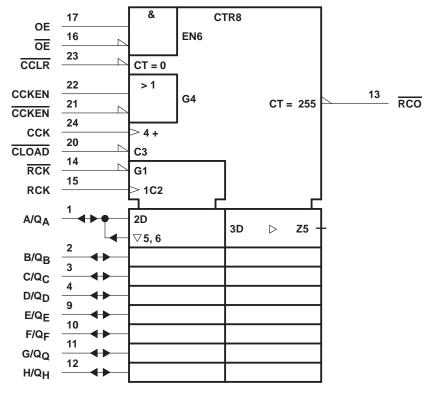
INP	UTS	OUTPUTS
CCKEN	CCKEN	A/Q <sub>A</sub> THRU H/Q <sub>H</sub>
L	L	Enable
L	Н	Disable
Н	L	Enable
Н	Н	Enable

#### **OUTPUT ENABLE**

INP	UTS	OUTPUTS
OE	OE	A/Q <sub>A</sub> THRU H/Q <sub>H</sub>
L	L	Input mode
L	Н	Input mode
Н	L	Output mode
Н	Н	Input mode

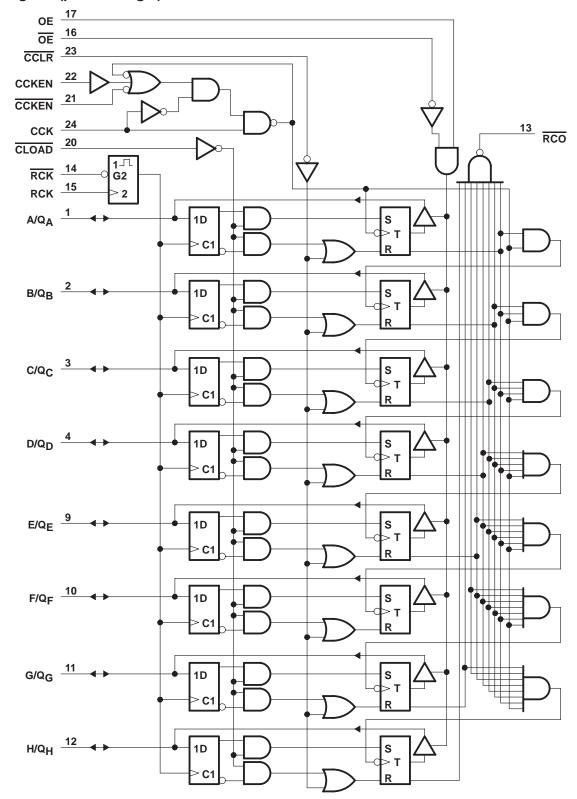
EPIC is a trademark of Texas Instruments Incorporated.

### logic symbol†

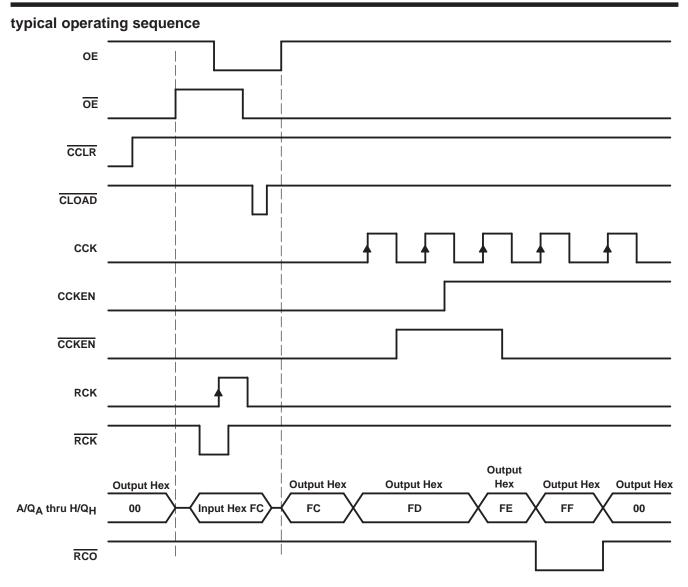


 $<sup>\</sup>ensuremath{^{\dagger}}$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)







## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	± 20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	± 50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	± 50 mA
Continuous current through V <sub>CC</sub> or GND	± 225 mA
Storage temperature range	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



### recommended operating conditions (see Note 2)

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	V
		V <sub>CC</sub> = 3 V	2.1			
$\vee_{IH}$	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			V
		$V_{CC} = 5.5 V$	3.85			
		V <sub>CC</sub> = 3 V			0.9	
VIL	Low-level input voltage	$V_{CC} = 4.5 V$			1.35	V
		V <sub>CC</sub> = 5.5 V			1.65	
VI	Input voltage		0		VCC	V
Vo	Output voltage		0		VCC	V
		V <sub>CC</sub> = 3 V			- 4	
ЮН	High-level output current	$V_{CC} = 4.5 V$			- 24	mA
		V <sub>CC</sub> = 5.5 V			-24	
		V <sub>CC</sub> = 3 V			12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V			24	mA
ЮН		V <sub>CC</sub> = 5.5 V			24	
Δt/Δν	Input transition rise or fall rate		0		10	ns/V
TA	Operating free-air temperature		- 40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	Т,	Δ = 25°C	;	MAINI	MAY	UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	IVIIIV	IVIAA	UNIT
		3 V	2.9			2.9		
	ΙΟΗ = – 50 μΑ	4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
VOH IC	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		V
	Jour 24 mA	4.5 V	3.94			3.8		
	10H = - 24 IIIA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I <sub>OL</sub> = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		3 \ 2.9						
VOL	IOH = -50 μA   IOH = -4 mA   IOH = -75 mA $^{\dagger}$   IOH = -75 mA $^{\dagger}$   IOH = -75 mA $^{\dagger}$   IOH = -24 mA   IOH = -75 mA $^{\dagger}$   IOH = -12 mA   IOH = -12	0.44	V					
$V_{OH} = -50 \mu\text{A} \qquad \qquad \begin{array}{c} 4.5  \text{V} & 4.5  \text{V} \\ 5.5  \text{V} & 5.5  \text{V} \\ \hline \\ I_{OH} = -4 \text{mA} & 3  \text{V} & 2.5  \text{V} \\ \hline \\ I_{OH} = -24 \text{mA} & 5.5  \text{V} & 4.9  \text{V} \\ \hline \\ I_{OH} = -75 \text{mA}^{\dagger} & 5.5  \text{V} \\ \hline \\ I_{OL} = 50 \mu\text{A} & 4.5  \text{V} \\ \hline \\ I_{OL} = 12 \text{mA} & 3  \text{V} \\ \hline \\ I_{OL} = 24 \text{mA} & 3  \text{V} \\ \hline \\ I_{OL} = 75 \text{mA}^{\dagger} & 5.5  \text{V} \\ \hline \\ I_{OL} = 75 \text{mA}^{\dagger} & 5.5  \text{V} \\ \hline \\ I_{OZ} & V_{O} = V_{CC} \text{or GND} & 5.5  \text{V} \\ \hline \\ I_{CC} & V_{I} = V_{CC} \text{or GND}, & I_{O} = 0 & 5.5  \text{V} \\ \hline \end{array}$			0.36		0.44			
	10L = 24 111A	NIN TYP MAX   2.9   2.9   4.5 V   4.4   5.5 V   5.4   5.4   5.5 V   3.94   3.8   5.5 V   4.94   4.8   5.5 V   3.85   3 V   0.1   0.1   4.5 V   0.1   0.1   5.5 V   0.1   0.1   3 V   0.36   0.44   V   4.5 V   0.36   0.44   5.5 V   0.36   0.44   5.5 V   5.5 V   1.65   5.5 V   ± 0.1   ± 1   μA   5.5 V   ± 0.5   ± 5   μA   5.5 V   8   80   μA   4.5 V   6.5 V   5.5 V						
	I <sub>OL</sub> = 75 mA <sup>†</sup>	5.5 V				2.9 4.4 5.4 2.48 3.8 4.8 3.85 0.1 0.1 0.1 0.1 0.44 0.44 1.65 ± 1  ± 5   # 80		
l <sub>l</sub>	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			± 0.1		± 1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V			± 0.5		± 5	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		4.5				pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 25°C MIN MAX		MIN MAX		UNIT
					IVIIIV	WAX	UNIT
fclock	Clock frequency, CCK or RCK			40		40	MHz
		CCK high or low	6		6		
		RCK high or low	6		6		
t <sub>W</sub>	Pulse duration	RCK high or low	4.5		4.5		ns
		CCLR low	7.5		7.5		
		CLOAD low	6.1		6.1		
	Setup time	CCKEN low before CCK↑	5.2		5.2		
		CCKEN high before CCK↑	6.4		6.4		
		CCLR high before CCK↑	1.7		1.7		
t <sub>su</sub>		CLOAD high before CCK↑	8.2		8.2		ns
		RCK↑ before CLOAD↑†	11.1		11.1		
		Data A thru H before RCK↑	2.3		2.3		
4.	Hold time	Data A thru H after RCK↑	0.5		0.5		no
th	Hold time	All others	0.2		0.2		ns

# timing requirements over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

			T <sub>A</sub> = 25°C		MIN	MAY	UNIT	
			MIN			MAX	UNII	
f <sub>clock</sub>	Clock frequency, CCK or RCK			70		70	MHz	
		CCK high or low	5		5			
		RCK high or low	5		5			
t <sub>W</sub>	Pulse duration	RCK high or low	4.5		4.5		ns	
		CCLR low	5		5			
		CLOAD low	4.7		4.7			
		CCKEN low before CCK↑	3.1		3.1			
		CCKEN high before CCK↑	4.3		4.3			
	Catua tima	CCLR high before CCK↑	1.1		1.1			
t <sub>su</sub>	Setup time	CLOAD high before CCK↑	5.4		5.4		ns	
		RCK <sup>↑</sup> before CLOAD <sup>↑</sup> <sup>†</sup>	7.8		7.8			
		Data A thru H before RCK↑	2		2			
4.	I lold time	Data A thru H after RCK↑	1.1		1.1			
<sup>t</sup> h	Hold time	All others	0.8		0.8		ns	

<sup>†</sup>This time insures the data saved by RCK↑ will also be loaded into the counter.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ТО	Т,	Δ = 25°C	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)		TYP	MAX	IVIIIV	WAX	UNII
f <sub>max</sub>			40			40		MHz
<sup>t</sup> PLH	ССК	Q	6.8	14.4	19.3	6.8	22.4	ns
<sup>t</sup> PHL	COR	ų ,	6.4	14.1	18.8	6.4	21.1	115
<sup>t</sup> PLH	CLOAD	Q	6.7	17.3	23.6	6.7	27.1	ns
<sup>t</sup> PHL	CLOAD	ų ,	3.9	18.9	29.1	3.9	32.3	115
<sup>t</sup> PHL	CCLR	Q	5.4	13	17.6	5.4	19.8	ns
<sup>t</sup> PZH	OE	Q	7.3	15.7	20.8	7.3	24.1	ns
t <sub>PZL</sub>	OL	ų ,	8	17.7	23.2	8	26.7	7 115
<sup>t</sup> PZH	ŌĒ	Q	6.9	15.2	20.2	6.9	23.3	ns
t <sub>PZL</sub>	OE	ų .	7.8	17.3	22.7	7.8	26.1	113
<sup>t</sup> PHZ	OE	Q	6.4	10.3	13.8	6.4	15.2	ns
t <sub>PLZ</sub>	OL.	<u> </u>	6.6	10.8	14.1	6.6	16.1	113
<sup>t</sup> PHZ	ŌĒ	Q	5.7	9.6	12.8	5.7	14.1	ns
t <sub>PLZ</sub>	OL .	<u> </u>	5.9	10.2	13.4	5.9	15.2	113
<sup>t</sup> PLH	CCK	RCO	5.3	12	16	5.3	18.6	ns
<sup>t</sup> PHL	OOK	, KCO	7.1	15.4	20.3	7.1	23.1	113
<sup>t</sup> PLH	CLOAD	RCO	5.9	12.4	16.5	5.9	18.8	ns
<sup>t</sup> PHL		RCO	10.1	19.6	25.5	10.1	29.4	113
<sup>t</sup> PLH	CCLR	RCO	5.6	12.3	16.6	5.6	19.2	ns
<sup>t</sup> PLH	RCK	RCO	8.6	17.3	22.2	8.6	25.8	ns
t <sub>PHL</sub>	NON.	KCO	10.3	20.3	26.2	10.3	30.3	115

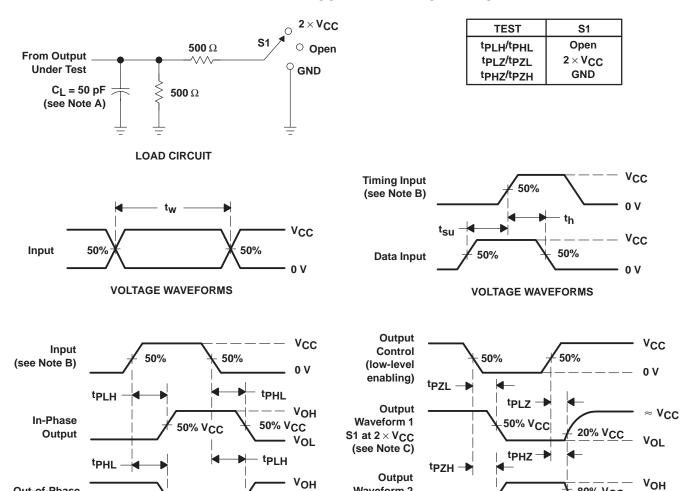
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ом то	Т,	Δ = 25°C	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	WAX	UNII
f <sub>max</sub>			70			70		MHz
t <sub>PLH</sub>	CCK	Q	4.1	8.7	12.4	4.1	14.3	ns
<sup>t</sup> PHL	COR	Q	4.2	8.9	12.6	4.2	14.2	115
<sup>t</sup> PLH	CLOAD	Q	3.7	10	15.3	3.7	17.4	ns
<sup>t</sup> PHL	CLOAD	Q	3.4	11.4	18.3	3.4	20.6	115
<sup>t</sup> PHL	CCLR	Q	3.3	7.9	11.8	3.3	13.4	ns
<sup>t</sup> PZH	OE	Q	4.1	9.1	13.2	4.1	15.3	ns
t <sub>PZL</sub>	OL	Q	4.1	9.4	13.8	4.1	16	6
<sup>t</sup> PZH	ŌĒ	Q	3.8	8.7	13	3.8	15	ns
t <sub>PZL</sub>	OE	Q .	3.9	9.1	13.4	3.9	15.4	115
<sup>t</sup> PHZ	OE	Q	4.2	7.6	10.6	4.2	11.6	ns
<sup>t</sup> PLZ	OL.	<u> </u>	5.3	8.8	11.8	5.3	13.1	113
<sup>t</sup> PHZ	ŌĒ	Q	4.4	7.3	10.1	4.4	11	ns
t <sub>PLZ</sub>	OE .	Q	5.2	8.5	11.6	5.2	13	113
<sup>t</sup> PLH	CCK	RCO	3.5	7.6	11.2	3.5	12.8	ns
<sup>t</sup> PHL	OOK	RCO	4.1	9.2	13.4	4.1	15.4	15.4 ns
<sup>t</sup> PLH	CLOAD	RCO	3.5	7.8	11.2	3.5	12.8	ns
<sup>t</sup> PHL	CLOAD		5.6	11.7	16.6	5.6	19	113
<sup>t</sup> PLH	CCLR	RCO	3.6	8	11.6	3.6	13.4	ns
<sup>t</sup> PLH	RCK	RCO	5	10.3	14.4	5	16.7	ns
<sup>t</sup> PHL	NON	, , , , , , , , , , , , , , , , , , ,	5.5	11.7	16.6	5.5	19.2	113

## operating characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CON	TYP	UNIT		
C <sub>pd</sub> Power dissipation capacitance	Dower dissinction conscitons	Outputs enabled	C: 50 pF	f 1 MI I-	66	F
	Power dissipation capacitance	Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	15	pF

### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

50% V<sub>C</sub>C

**VOLTAGE WAVEFORMS** 

Out-of-Phase

Output

B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_{O} = 50 \Omega$ ,  $t_{f} = 3 \text{ ns}$ ,  $t_{f} = 3 \text{ ns}$ .

Waveform 2

(see Note C)

S1 at GND

- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

50% V<sub>C</sub>C

 $v_{OL}$ 

Figure 1. Load Circuit and Voltage Waveforms



۷он

0 V

80% V<sub>CC</sub>

50% V<sub>C</sub>C

**VOLTAGE WAVEFORMS** 

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